

INTERNATIONAL CMOS TECHNOLOGY, INC.

T-46-19-07

PEEL[™]18CV8

CMOS Programmable Electrically Erasable Logic Device

Features

- Advanced CMOS EEPROM Technology
- **Low Power Consumption**
 - 20mA standby + 0.7mA/MHz max
- High Performance
 - tpp = 25ns max, fmax=33.3MHz
- **■** EE Instant Reprogrammability
 - 100% factory tested
 - Cost-effective windowless package
 - Erases and programs in seconds
 - Adds convenience, reduces field retrofit and development costs
- Foolproof Design Security
 - Prevents unauthorized reading or copying

- Architectural Flexibility
 - 74 product term x 36 input array

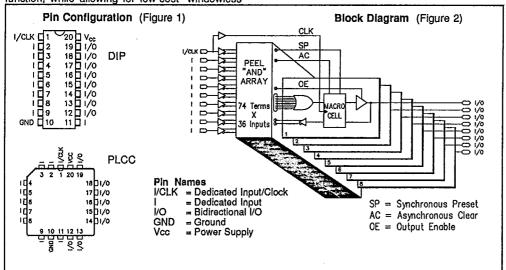
 - Up to 18 inputs and 8 I/O pins Independent configurable I/O macro cells
 - Synchronous preset, asynchronous clear
 - Independent output enables
- Application Versatility

 - Replaces SSI/MSI logic Emulates bipolar PAL* devices, GAL*
 - devices, and EPLDs Simplifies inventory control
 - Allows new design possibilities
- Development/Programmer Support
 - Third party software and programmers
 - ICT PEEL Development System and

General Description

The ICT PEEL18CV8 is a CMOS Programmable Electrically Erasable Logic device that provides a high-performance, low-power, reprogrammable, and architecturally flexible alternative to earlygeneration programmable logic devices (PLDs).
Designed in advanced CMOS EEPROM technology, the performance of the PEEL18CV8 rivals speed parameters of bipolar PLDs with a dramatic reduction in power consumption. EE reprogrammability simplifies inventory management, reduces development and field retrofit costs, enhances testability to ensure 100% field programmability and function, while allowing for low-cost "windowless"

packaging in a 20-pin, 300-mil DIP. The PEEL18CV8's flexible architecture allows the device to replace SSI/MSI logic circuitry. ICT's JEDEC file translator allows the PEEL18CV8 to replace existing 20-pin PLDs without the need to rework the existing design. Development and programming support for the PEEL18CV8 is provided by popular third-party PC-based development tools and programmers from third-party manufacturers. ICT also offers a free design software package and a low-cost development sys-



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Function Description

The PEEL18CV8 implements logic functions as sum-of-products expressions in a programmable-AND/fixed-OR logic array. User-defined functions are created by programming the connections of input signals into the array. User-configurable output structures in the form of I/O macrocells further increase logic flexibility.

Architecture Overview

The PEEL18CV8 architecture is illustrated in the block diagram of figure 2. Ten dedicated inputs and 8 I/Os provide up to 18 inputs and 8 outputs for creation of logic functions. At the core of the device is a programmable electrically-erasable AND array which drives a fixed OR array. With this structure the PEEL18CV8 can implement up to 8 sum-of-products logic expressions.

Associated with each of the 8 OR functions is an I/O macrocell which can be independently programmed to one of 12 different configurations. The programmable macrocells allow each I/O to create sequential or combinatorial logic functions of active-high or active-low polarity, while providing three different feedback paths into the AND array.

AND/OR Logic Array

The programmable AND array of the PEEL18CV8 (shown in figure 3) is formed by input lines intersecting product terms. The input lines and product terms are used as follows:

36 Input Lines:

20 input lines carry the true and compliment of the signals applied to the 10 input pins

16 additional lines carry the true and compliment values of feedback or input signals from the 8 I/Os

74 product terms:

64 product terms (arranged in groups of 8) used to form sum of product functions

8 output enable terms (one for each I/O)

1 global synchronous preset term

1 global asynchronous clear term

At each input-line/product-term intersection there is an EEPROM memory cell which determines whether or not there is a logical connection at that intersection. Each product term is essentially a 36-input AND gate. A product term which is connected to both the true and compliment of an input signal will

always be FALSE and thus will not effect the OR function that it drives. When all the connections on a product term are opened, a don't care state exists and that term will always be TRUE.

When programming the PEEL18CV8, the device programmer first performs a bulk erase to instantly remove the previous pattern. The erase cycle opens every logical connection in the array. The device is configured to perform the user-defined function by programming selected connections in the AND array. (Note that PEEL device programmers automatically program all of the connections on unused product terms so that they will have no effect on the output function)

Programmable I/O Macrocell

The unique twelve-configuration output macrocell provides complete control over the architecture of each output. The ability to configure each output independently permits users to tailor the configuration of the PEEL18CV8 to the precise requirements of their designs.

Macrocell Architecture

Each I/O macrocell, as shown in figure 4, consists of a D-type flip-flop and two signal-select multiplexers. The configuration of each macrocell is determined by the four EEPROM bits controlling these multiplexers. These bits determine: output polarity; output type (registered or non-registered); and input/feedback path (bi-directional I/O, combinatorial feedback, or register feedback). Refer to table 1 for details.

Equivalent circuits for the twelve macrocell configurations are illustrated in figure 5. In addition to emulating the four PAL-type output structures (configurations 3, 4, 9, and 10) the macrocell provides eight additional configurations. When creating a PEEL device design, the desired macrocell configuration generally is specified explicitly in the design file. When the design is assembled or compiled, the macrocell configuration bits are defined in the last lines of the JEDEC programming file.

Output Type

The signal from the OR array can be fed directly to the output pin (combinatorial function) or latched in the D-type flip-flop (registered function). The D-type flip-flop latches data on the rising edge of the clock and is controlled by the global preset and clear terms. When the synchronous preset term is satisfied, the Q output of the register will be set HIGH at the next rising edge of the clock input. Satisfying the asynchronous clear term will set Q LOW, regardless of the clock state. If both terms are satisfied simultaneously, the clear will override the preset.

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Output Polarity

Each macrocell can be configured to implement active-high or active-low logic. Programmable polarity eliminates the need for external inverters.

Output Enable

The output of each I/O macrocell can be enabled or disabled under the control of its associated programmable output enable product term. When the logical conditions programmed on the output enable term are satisfied, the output signal is propagated to the I/O pin. Otherwise, the output buffer is driven into the high-impedance state.

Under the control of the output enable term, the I/O pin can function as a dedicated input, a dedicated output, or a bi-directional I/O. Opening every connection on the output enable term will permanently enable the output buffer and yield a dedicated output. Conversely, if every connection is intact, the enable term will always be logically false and the I/O will function as a dedicated input.

input/Feedback Select

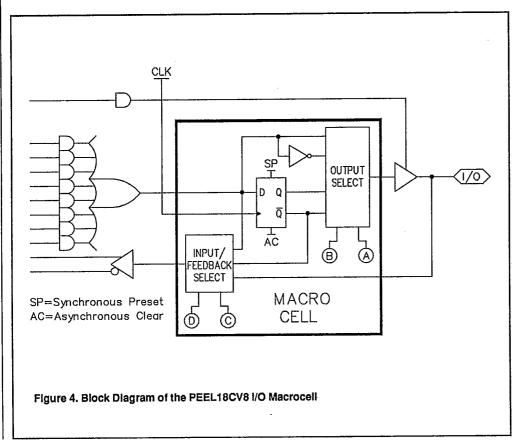
The PEEL18CV8 macrocell also provides control over the feedback path. The input/feedback signal associated with each I/O macrocell may be obtained from three different locations: from the I/O pin (bi-directional I/O); directly from the Q output of the flip-flop (registered feedback); or directly from the OR gate (combinatorial feedback).

Bi-directional I/O

The input/feedback signal is taken from the I/O pin when using the pin as a dedicated input or as a bi-directional I/O. (Note that it is possible to create a registered output function with bi-directional I/O.)

Combinatorial Feedback

The signal-select multiplexer gives the macrocell the ability to feedback the output of either the OR gate, bypassing the output buffer, regardless of whether the output function is registerd or combinatorial. This feature allows the creation of asynchronous latches,



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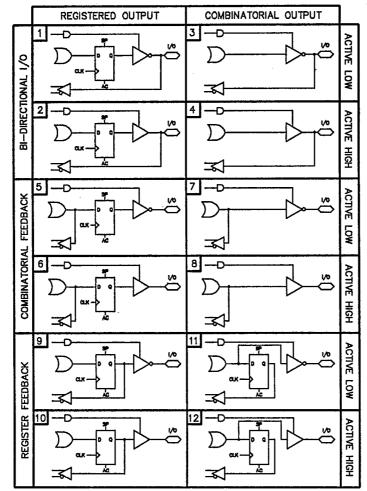


Figure 5. Equivalent Circuits for the Twelve Configurations of the PEEL18CV8 I/O Macrocell.

Configuration		Input/Feedback Select	Output Select				
#	ABCD	•	· ·				
1	1111	Bi-Directional I/O	Register	Active Low			
2	0 1 1 1	и	*	Active High			
3	1 0 1 1	"	Combinatorial	Active Low			
4	0 0 1 1	н	"	Active High			
5	1110	Combinatorial Feedback	Register	Active Low			
6	0 1 1 0	"	н	Active High			
7	1 0 1 0	¥	Combinatorial	Active Low			
8	0 0 1 0	H.	м	Active High			
9	1 1 0 0	Register Feedback	Regisiter	Active Low			
10	1 1 0 0	н	"	Active High			
11	1 0 0 0	n n	Combinatorial	Active Low			
12	0000	ਜ	н	Active High			

Table 1. PEEL18CV8 Macrocell Configuration Bits

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Bi-directional I/O

The input/feedback signal is taken from the I/O pin when using the pin as a dedicated input or as a bi-directional I/O. (Note that it is possible to create a registered output function with bi-directional I/O.)

Combinatorial Feedback

The signal-select multiplexer gives the macrocell the ability to feedback the output of either the OR gate, bypassing the output buffer, regardless of whether the output function is registerd or combinatorial. This feature allows the creation of asynchronous latches, even when the output must be disabled. (Refer to configurations 5, 6, 7, and 8 in figure 5.)

Registered Feedback

Feedback also can be taken from the register, regardless of whether the output function is to be

combinatorial or registered. When implementing combinatorial output function, registered feedback allows for the internal latching of states without giving up the use of the external output.

Design Security

The PEEL18CV8 provides a special EEPROM security bit that prevents unauthorized reading or copying of designs programmed into the device. The security bit is set by the PLD programmer, either at the conclusion of the programming cycle or as a separate step, after the device has been programmed. Once the security bit is set it is impossible to verify (read) or program the PEEL until the entire device has first been erased with the bulk-erase function.

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Absolute Maximum Ratings

Exposure to absolute maximum ratings over extended periods of time may affect device reliability. Exceeding absolute maximum ratings may cause permenant damage

Symbol Parameter		Conditions	Rating	Unit	
Vcc	Supply Voltage	Relative to GND	- 0.5 to + 7.0	V	
Vı, Vo	Voltage Applied to Any Pin ⁶	Relative to GND ¹	- 0.5 to Vcc + 0.6	V	
lo	Output Current	Per pin (lot, loн)	± 25	mA	
Тэт	Storage Temperature		- 65 to + 125	.c	
TLT	Lead Temperature	Soldering 10 seconds	+ 300	.c	

Operating Ranges²

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Symbol	Parameter	Conditions	Min	Max	Unit
Vcc	Supply Voltage	Commercial	4.75	5.25	V
		Industrial	4.5	5.5	V
TA	Ambient Temperature	Commercial	0	+ 70	°C
	•	Industrial	- 40	+ 85	.c
TR	Clock Rise Time	See note 4		250	ns
TF	Clock Fall Time	See note 4		250	ns
TRVCC	Vcc Rise Time	See note 4		250	ms

D.C. Electrical Characteristics Over the operating range

Symbol	Parameter	Conditions	Min	Max	Unit	
Voн	Output HIGH Voltage - TTL	Vcc = Min, loH = - 4.0mA	2.4			
Vонс	Output HIGH Voltage-CMOS	Vcc = Min, IoH = -10μA	Vcc - 0.1		٧	
Vol	Output LOW Voltage - TTL	Vcc = Min, lot = 8mA		0.45	٧	
Volc	Output LOW Voltage-CMOS	Vcc = Min, loL = 10μA		0.1	٧	
ViH	Input HIGH Level		2.0	Vcc + 0.3	٧	
VIL	Input LOW Level		- 0.3	0.8	٧	
lı <u>.</u>	Input Leakage Current	Vcc = Max, GND ≤ Vin ≤ Vcc	· · · · · · ·	±10	μΑ	
loz	Output Leakage Current	VO = High-Z, GND ≤ Vo≤ Vcc		±10	μΑ	
Isc	Output Short Circuit Current	Vcc = Max, Vo = 0.5V 10	- 30	- 100	mA	
Iccsc	Vcc Current, Standby, CMOS	V _{IN} = V _{CC} or GND ⁵		20 (30)*	mA	
Iccac ¹	Vcc Current, Active, CMOS	V _{IN} = Vcc or GND. All outputs open. ^{5,11}		lccsc + 0.7mA/MHz	mA	
lccst	Vcc Current, Standby, TTL	VIN = VIL or VIH 5,11		25 (35)*	mA	
ICCAT ¹	V _{CC} Current, Active, TTL	V _{IN} = V _{IL} or V _{IH} . All outputs open. ⁵		Iccsr+ 0.7mA/MHz	mA	
CiN 8	Input Capacitance	T _A = 25°C, V _{CC} = 5.0V		6	pF	
Cout 8	Output Capacitance	@ f = 1MHz		12	рF	

^{*} Numbers in parenthesis specify parameters for industrial temperature range.

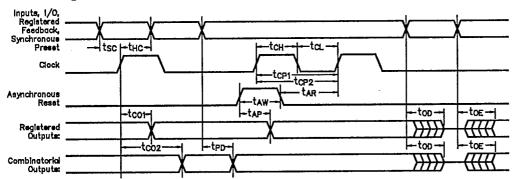


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A.C. Electrical Characteristics Over the Operating Range^{3,12}

Symbol	Parameter	18C\	18CV8-25		18CV8-30		18CV8-35	
		Min	Max	Min	Max	Min	Max	
tPD	Input ⁴ or feedback to non-registered output		25		30		35	nS
toE	Input ⁴ to output enable ⁶		25		30		35	nS
top	Input ⁴ to output disable ⁶		25		30		35	пS
tco1	Clock to output		15		20		20	nS
tcoz	Clock to combinatorial output delay via internal registered feedback		35		45		50	nS
tsc	Input ⁴ or feedback setup to clock	20		25		30		nS
tнç	input ⁴ hold after clock	0		0		0		nS
tcl,tch	Clock width - clk low time, clk high time 5	15		15		15		nS
tcP1	Clock period (register feedback to registered output via internal path)	30		40		45		nS
f _{max1}	Maximum clock frequency (1/tcp1)	33.3		25		22.2		MHz
t _{CP2}	Clock period (tsc + tco1)	35		45		50		nS
f _{max2}	Maximum clock frequency (1/tcp2)	28.5		22.2		20		MHz
taw	Asynchronous clear pulse width	25		30		35		nS
tap	Input ⁴ to asynchronous clear		30		35		40	nS
tar	Asynchronous Reset Recovery Time		20		35		30	nS
TRESET	Power-on reset time for registers in clear state		5		5		5	μS

Switching Waveforms



- Minimum DC input is -0,5V, however inputs may undershoot to -2.0V for periods less than 20ns
 Contact ICT for other operating ranges.

- Contact ICT for other operating ranges. (Industrial, Mil-temp.) Vi and Vo are not specified for program/verify operation. Test points for Clock and Voc in th, tr, tcl, tch, and theset are referenced at 10% and 90% levels. I/O pins are open (no load). Input refers to Input pin signal. toe is measured from input transition to VREF ± 0.1V, top is measured from input transition to VOH-0.1V or VOL+0.1V; VREF = VL see test loads at the end of this section.
- Capacitance are tested on a sample basis.
- Test conditions assume: signal transition times of 5ns or less from the 10% and 90% points, timing reference levels of 1.5V (unless otherwise specified).
- 10. Test one output at a time for a duration less than 1 second.
- 11. ICC for a typical application: This parameter is tested with the device programmed as an 8-bit counter.
- 12. PEEL Device test loads are specified at the end of this section.